DfX for Nanoelectronic Embedded Systems

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Computing Evolution

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Ancient Computing Machines -- Mechanical



2400 BC

- -- The abacus
- -- The first known calculator
- -- Invented in Babylonia



1832 AD

-- The Babbage Difference Machine

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- -- Tabulated polynomial functions
- -- Invented in Britain

The First Electronic Computer



1946

UNT

- -- ENIAC -- The first electronic general-purpose computer.
- -- Turing-complete, digital, and programmable.
- -- Invented in USA.



Smallest Single-Board Computers



Raspberry Pi

BeagleBone

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The Workhorses

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Variety of Integrated Circuits or Chips?



Intel Core i7 LGA1366 processor has 1366 pins.

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ADC Chip

Intel Haswell Chip -- 2013 4th Generation Intel[®] Core[™] Processor Die Map 22nm Tri-Gate 3-D Transistors



GPU with Highest Transistor Count



Nvidia GK110 has 7.1 billion transistors of a 28nm technology.

Source: http://www.tomshardware.com/news/nvidia-tesla-k20-gk110-gpu,15683.html

Processor for Mobile Systems: Essentially AMS-SoCs



NVIDIA's Tegra 2 die

Source: http://www.anandtech.com



Snapdragon S4 Block Diagram

Source: http://www.cnx-software.com

The Drivers

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Technology Miniaturization (aka Technology Scaling) Nano

New Technology ⁵⁻ (Alternative Devices)



How Small in Nano??



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"nano" means onebillionth, or 10⁻⁹

 A sheet of paper is about 100,000 nanometers thick

A human hair is approx.
 100,000 nanometers wide

Source: http://www.nano.gov/nanotech-101/what/nano-size

A Typical Nanoelectronic System



Good and Bad,

and DFX

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Scaling Reduces Power Dissipation



1 Virtex-7 2000T = 4 Largest Monolithic FPGAs 19 Watts 112 Watts

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Source: http://low-powerdesign.com/sleibson

18

Scaling Reduces Cost of Electronics

In 1986: 1.3 megapixels CCD sensor Kodak camera was \$13,000. You can buy now for few dollars.



Nikon D7000 DSLR camera.

16 MP → \$700

Source: http://www.lensrentals.com/blog/2012/04/d7000-dissection

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DfX -- Design for X (aka Design for Excellence)

- **X** = set of IC design challenges
 - Manufacturability
 - Power
 - Variability
 - Cost
 - Yield
 - Reliability
 - Test
 - Debug

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Source: ISVLSI 2012 Andrew Kahng Keynote

Design for Power

(DfP)

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Consumer Electronics Demand More and More Energy



Different Electronic Systems: Common Story







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Smarter … Faster … High Throughput …
 → Power Hungry !! Battery Hungry !!

Battery Dependency: Not Overstated



In flight, the airplane is powered by electricity produced by the engine generators. The batteries are part of the multiple layers of redundancy that would ensure power in the extremely unlikely event of a power failure.

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One 787 Battery: 12 Cells / 32 V DC



Boeing 787's across the globe were grounded in early 2013.

Source: http://www.newairplane.com

Battery Dependency: Not Overstated



Great idea: Smartwatch with functioning like smartphone.

Big Problem: Battery life of one time charging is only 1 day.

Source: http://www.businessinsider.com

A Typical Electronic System: Where Energy Consumed??

Power of a Mobile System



DfP: Possible Solution Fronts



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DfP: Design of an Universal Level Converter for Dynamic Power Management



One Example Electronic System: Secure Digital Camera



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Universal Voltage-Level Converter: One Topology



- 20 transistor area efficient design.
- Energy hungry transistors are circled.

- Energy hungry transistors have thicker oxide.
- 90nm CMOS dual-oxide physical design of ULC.



Universal Voltage-Level Converter: Operations

Operations of the ULC:

- Level-up conversion
- Level-down conversion
- Blocking of input signal

Select Signal		Type of Operation	
0	0	Block Signal	
0	1	Up Conversion	
1	0	Down Conversion	

38



Universal Voltage-Level Converter: Has Minimal Overhead

Designs	Technology (nm)	Power	Delay	Conversion	Design Approach
Ishihara 2004	130nm		127 ps	Level-up and down	Level converting flip flops
Yu 2001	350nm	220.57 μW		Level-up	SDCVS
Sadeghi 2006	100nm	10 µW	1 ns	Level-up	Pass transistor and Keeper transistor
ULC	90 nm	12.26 μW	113.8 ps	Level- up/down and block	All conversion types and Programmable

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Design for Variability (DfV)

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Nanoelectronics Variability ?

Discrepancy between the chip parameters - Design Time versus Actual Post Fabrication



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Source: http://apcmag.com/picture-gallery-how-a-chip-is-made.htm

Process Variation: Parameters



Source–drain resistance is different for different chips in a same die.



Gate-to-source and gate-to-drain overlap capacitance is different for different chips in a same die.

Source: Bernstein et al., IBM J. Res. <u>& Dev., July/Sep 2006</u>.



Process Variation: The Impact

- Yield Loss
- Reliability Issue
- Higher Cost



Process Variation: Sources



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Sophisticated Lithography

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45





DfV: Statistical Nano-CMOS RTL Optimization for Power



Nano-CMOS RTL Statistical Optimization



Statistical RTL Optimization: Formulation

Minimize: $FoM_{Total}^{DFG}(\mu_{I}^{DFG}, \sigma_{I}^{DFG})$

Subjected to (Resource/Time Constraints): Allocated $(FU_{k,i}) \le$ Available $(FU_{k,i}), \forall$ cyclec $D_{CP}^{DFG}(\mu_D^{DFG}, \sigma_D^{DFG}) \le D_{Con}(\mu_D^{Con}, \sigma_D^{Con})$

Statistical RTL Optimization: Results on DSP Benchmarks



(For BPF Benchmark)

Design for Cost (\$) (DfC)

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One of the Key Issues: Time/Effort

The simulation time for a Phase-Locked-Loop (PLL) lock on a full-blown (RCLK) parasitic netlist is of the order of many days! → High NRE cost.



PLL

Issues for AMS-SoC components:

- How fast can design space exploration be performed?
- How fast can layout generation and optimization be performed?

Standard Design Flow – Very Slow



Standard design flow requires multiple manual iterations on the back-end layout to achieve parasitic closure between front-end circuit and back-end layout. Longer design cycle time. Error prone design. Higher non-recurrent cost. Difficult handle to nanoscale challenges.

Automatic Optimization on Netlist (Faster than manual flow; still slow)





Proposed Flow: Key Perspective

- Novel design and optimization methodology that will produce robust AMS-SoC components using ultra-fast automatic iterations over metamodels (instead of netlist) and two manual layout steps.
- The methodology easily accommodates multidimensional challenges, reduces design cycle time, improves circuit yield, and reduces chip cost.

Metamodel-Based Design Flow



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65



Metamodels : Polynomial Example



Sampling Techniques: 45nm Ring **Oscillator Circuit (5000 points)**

Monte Carlo









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Polynomial Metamodels

- The generated sample data can be fitted in many ways to generate a metamodel.
- The choice of fitting algorithm can affect the accuracy of the metamodel.
- A simple metamodel has the following form:

$$y = \sum_{i,j=0}^{k} \left(\alpha_{ij} \times x_1^i \times x_2^j \right)$$

y is the response being modeled (e.g. frequency), $x = [W_n, W_p]$ is the vector of variables and α_{ij} are the coefficients.

Metamodel: Polynomial Comparison

Case Study	Polynomial	μ error	σ error
Circuits	Order	(in MHz)	(in MHz)
	1	571.0	286.7
Ring Oscillator	2	195.4	78.1
King Osemator	3	37.2	18.0
45nm CMOS	4	20.0	10.7
Target f : 10GHz	5	17.1	9.6
	1	42.3	40.1
I C-VCO	2	39.4	37.8
Leveo	3	35.4	33.9
180nm CMOS	4	30.5	29.3
Target <i>f</i> : 2.7GHz	5	26.5	25.2

Ring oscillator – Order 1

LC-VCO – Order 1

$f(W_n, W_p)$	=	$7.94 \times 10^9 + 1.1 \times 10^{16} W_n$	$f(W_n, W_p)$	=	$2.38 \times 10^9 - 3.49 \times 10^{12} W_n$
		$+1.28 \times 10^{15} W_p.$			$-6.66 \times 10^{12} W_p.$

Artificial Neural Network (ANN) Metamodeling

- Feed-forward dual layer (FFDL) ANNs are considered.
- FFDL ANN created for each FoM:

 Nonlinear hidden layer functions are considered each varying hidden neurons 1-20:

 $b_j(v_j) = \tanh(\lambda v_j)$

Feed Forward Neural Network W_{jk} Wii Input Output Hidden Layer Layer Layer

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Metamodel Comparison: Polynomial Vs Nonpolynomial

 Nonpolynomial (Artificial Neural Network) is more suitable large circuits.

180nm CMOS PLL with Target Specs: f = 2.7GHz, P = 3.9mW, $8.5\mu s$.

Figures-of- Merits (FoM)	Polynomial # of Coefficients RMSE		Nonpolynomial (Neural Network)
Frequency	48	77.96 MHz	48MHz
Power	50	2.6mW	0.29mW
Locking Time	56	1.9µs	1.2µs

- 56% increase in accuracy over polynomial metamodels.
- On average 3.2% error over golden design surface.



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78

Exhaustive Search : 45nm RO

10 GHz Frequency Contour



Searches over two parameter space.

Parameters incremented over specified steps.



Comparison of the Running Time of Heuristic Algorithms: 45nm RO



- Optimizationwithoutmetamodels:the tabu searchoptimization is faster by ~1000×than the exhaustive search and~4× faster than the simulatedannealing optimization.
- Optimization with metamodels: the simulated annealing optimization is faster by ~1000× than the exhaustive search and ~6× faster than the tabu search optimization.

Case Study Circuit: 180nm PLL



Block diagram of a PLL.

- PLL circuit is characterized for frequency, power, vertical and horizontal jitter (for simple phase noise), and locking time.
- Metamodels are created for each FoM from same sample set.

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PLL for 180nm.

PLL: Polynomial Metamodels ...

- The number of coefficients corresponding to the order of the generated metamodel for settling time.
- This means that the model is over fitted, therefore for the metamodel that represents settling time, a polynomial order of 4 will be used.



Artificial Bee-Colony : Overview

1. Initial food sources are produced for all worker bees.

2. Do

- 1) Each worker bee goes to a food source and evaluates its nectar amount.
- 2) Each onlooker bee watches the dance of worker bees and chooses one of their sources depending on the dances and evaluates its nectar amount.
- 3) Determine abandoned food sources and replace with the new food sources discovered by scout bees.
- ⁴⁾ Best food source determined so far is recorded.
- 3. While (requirements are met)

A food source \rightarrow a solution; A position of a food source \rightarrow a design variable set; Nectar amount \rightarrow Quality of a solution; Number of worker bees \rightarrow number of quality solutions.

PLL: ABC over Poly. Metamodels

PLL parameters with constraints

and optimized values.

Circuit	Parameter	Min	Max	Optimal
		(m)	(m)	Value (m)
	W_{ppd1}	400n	2μ	1.66μ
	W_{npd1}	400n	2μ	1.11μ
Phase Detector	W_{ppd2}	400n	2μ	784n
Thase Detector	W_{npd2}	400n	2μ	689n
	W_{ppd3}	400n	2μ	1.54μ
	W_{npd3}	400n	2μ	737n
	W_{nCP1}	400n	2μ	1.24μ
Charge Pump	W_{pCP1}	400n	2μ	1.35μ
charge rump	W_{nCP2}	1μ	4μ	1.35μ
	W_{pCP2}	1μ	4μ	2.88μ
I C-VCO	W_{nLC}	3μ	20μ	18.62μ
10-700	W_{pLC}	6μ	40μ	37.48μ
	W_{p1Div}	400n	2μ	1.65μ
	W_{p2Div}	400n	2μ	1.54μ
	W_{p3Div}	400n	2μ	1.38μ
	W_{p4Div}	400n	2μ	1.96μ
Divider	W_{n1Div}	400n	2μ	1.09μ
	W_{n2Div}	400n	2μ	1.17μ
	W_{n3Div}	400n	-2μ	1.29μ
	W_{n4Div}	400n	2μ	1.95μ
	W_{n5Div}	400n	2μ	536n

 An exhaustive search of the design space of 21 parameters with 10 intervals per parameter requires 10²¹ simulations.

- 10²¹ SPICE simulations is slow; 10min per one.
- 10²¹ simulations using polynomial metamodels is fast.

Time savings: ≈10²⁰×
 SPICE simulation time.

PLL: ABC Optimization: Poly Vs ANN

Optimization Results

FoM	Poly. Metamodel	ANN Metamodel	
Average Power	3.9 mW	3.9 mW	
Frequency	2.6909 GHz	2.7026 GHz	

Optimization Time Comparison

Algorithm	Circuit Netlist	Poly. Metamodel	ANN Metamodel
ABC (100 iterations)	<pre>#bees(20) * 5 min * 100 iteration = 10,000 minutes = 7 days (worst case)</pre>	5 mins	0.12 mins
Metamodel Generation	0	11 hours for LHS + 1 min creation	11 hours for LHS + 10mins training and verification.

Conclusions

- Nanoelectronic circuits and systems have multifold design challenges.
- DfX is design for X Power, Variability, Cost …
- DfP:
 - □ 35% of total energy in USA is consumed by electronics.
 - Battery is an critical constraint for portable systems.
 - Energy efficient hardware, software at the same time better battery design needed for effective solutions.
- DfV: Reduce the variability in chip and enhance yield.
- DfC: Reduce NRE, yield, and time to market.

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■ Much more research is needed for combined consideration of issues, e.g. X ← Variability and Cost

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Thank You !!!

Slides Available at: http://www.cse.unt.edu/~smohanty